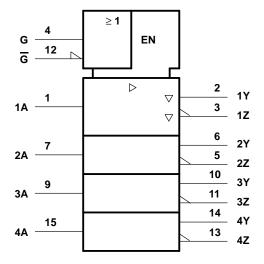
- Meets or Exceeds the Requirements of ANSI EIA/TIA-422-B and ITU Recommendation V.11
- Operates From a Single 5-V Supply
- TTL Compatible
- Complementary Outputs
- High Output Impedance in Power-Off Conditions
- Complementary Output Enable Inputs

### description

The AM26LS31C is a quadruple complementaryoutput line driver designed to meet the requirements of ANSI EIA/TIA-422-B and ITU (formerly CCITT) V.11. The 3-state outputs have high-current capability for driving balanced lines such as twisted-pair or parallel-wire transmission lines, and they provide a high-impedance state in the power-off condition. The enable function is common to all four drivers and offers the choice of an active-high or active-low enable input. Low-power Schottky circuitry reduces power consumption without sacrificing speed.

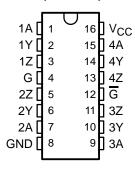
The AM26LS31C is characterized for operation from 0°C to 70°C.

# logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# D OR N PACKAGE (TOP VIEW)



# FUNCTION TABLE (each driver)

INPUT	ENA	ENABLES		PUTS
A	G	G	Y	Z
Н	Н	Χ	Н	L
L	Н	Χ	L	Н
Н	X	L	Н	L
L	X	L	L	Н
X	L	Н	Z	Z

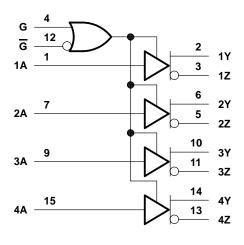
H = high level

X = irrelevant

L = low level

Z = high impedance (off)

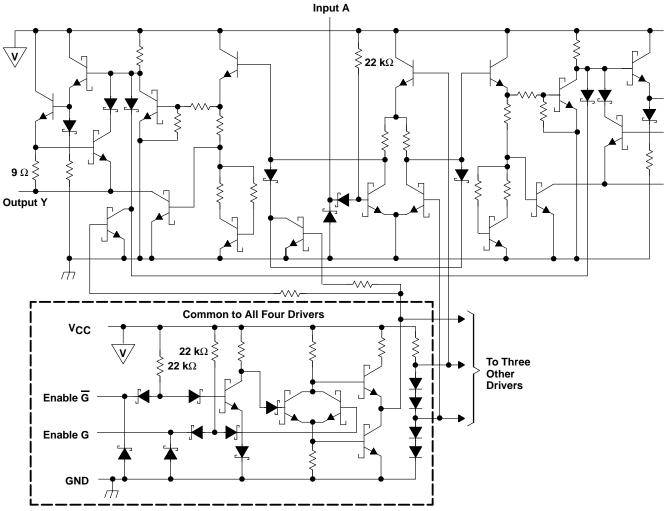
## logic diagram (positive logic)





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## schematic (each driver)



All resistor values are nominal.

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub> (see Note 1)	7 V
Input voltage, V <sub>I</sub>	7 V
Output off-state voltage	5.5 V
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T <sub>A</sub>	0°C to 70°C
Storage temperature range, T <sub>stq</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values, except differential output voltage VOD, are with respect to network GND.



### **DISSIPATION RATING TABLE**

PACKAGE	$T_{\mbox{A}} \le 25^{\circ}\mbox{C}$ POWER RATING	DERATING FACTOR ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING		
D	950 mW	7.6 mW/°C	608 mW		
N	1150 mW	9.2 mW/°C	736 mW		

# recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.75	5	5.25	V
High-level input voltage, VIH	2			V
Low-level input voltage, V <sub>IL</sub>			0.8	V
High-level output current, I <sub>OH</sub>			-20	mA
Low-level output current, IOL			20	mA
Operating free-air temperature, T <sub>A</sub>	0		70	°C

# electrical characteristics over operating free-air temperature range (unless otherwise noted)

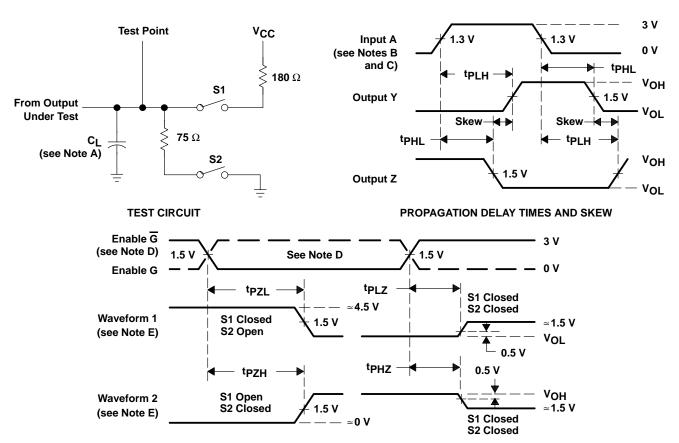
PARAMETER		TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
VIK	Input clamp voltage	$V_{CC} = 4.75 \text{ V},  I_{I} = -18 \text{ mA}$			-1.5	V
Vон	High-level output voltage	$V_{CC} = 4.75 \text{ V},  I_{OH} = -20 \text{ mA}$	2.5			V
VOL	Low-level output voltage	$V_{CC} = 4.75 \text{ V},  I_{OL} = 20 \text{ mA}$			0.5	V
	Off-state (high-impedance-state) output current	V <sub>CC</sub> = 4.75 V V <sub>O</sub> = 0.5 V			-20	^
loz		$V_{O} = 4.75 \text{ V}$ $V_{O} = 2.5 \text{ V}$			20	μΑ
II	Input current at maximum input voltage	$V_{CC} = 5.25 \text{ V},  V_{I} = 7 \text{ V}$			0.1	mA
ΙΗ	High-level input current	$V_{CC} = 5.25 \text{ V},  V_{I} = 2.7 \text{ V}$			20	μΑ
Ι <sub>Ι</sub> L	Low-level input current	$V_{CC} = 5.25 \text{ V},  V_{I} = 0.4 \text{ V}$			-0.36	mA
Ios	Short-circuit output current‡	V <sub>CC</sub> = 5.25 V	-30		-150	mA
ICC	Supply current	V <sub>CC</sub> = 5.25 V, All outputs disabled		32	80	mA

# switching characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT	
tPLH	Propagation delay time, low-to-high-level output	C <sub>L</sub> = 30 pF, See Figure 1	<u> </u>		14	20	ns	
tPHL	Propagation delay time, high-to-low-level output				S1 and S2 open,		14	20
	Output-to-output skew				1	6	ns	
<sup>t</sup> PZH	Output enable time to high level	C <sub>L</sub> = 30 pF, See Figure 1	$R_L = 75 \Omega$ ,		25	40	ns	
t <sub>PZL</sub>	Output enable time to low level	C <sub>L</sub> = 30 pF, See Figure 1	R <sub>L</sub> = 180 Ω,		37	45	ns	
<sup>t</sup> PHZ	Output disable time from high level	C <sub>L</sub> = 10 pF, See Figure 1	C <sub>L</sub> = 10 pF, S1 and S2 closed,		21	30	ns	
tPLZ	Output disable time from low level				23	35	ns	

<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V and T<sub>A</sub> = 25°C. ‡ Not more than one output should be shorted at a time, and duration of the short circuit should not exceed one second.

### PARAMETER MEASUREMENT INFORMATION



**ENABLE AND DISABLE TIME WAVEFORMS** 

NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O \approx 50~\Omega$ ,  $t_\Gamma \leq$  15 ns, and  $t_f \leq$  6 ns.
- C. When measuring propagation delay times and skew, switches S1 and S2 are open.
- D. Each enable is tested separately.
- E. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

Figure 1. Test Circuit and Voltage Waveforms

Figure 5

### TYPICAL CHARACTERISTICS

#### **OUTPUT VOLTAGE OUTPUT VOLTAGE** vs **ENABLE G INPUT VOLTAGE ENABLE G INPUT VOLTAGE** 4 V<sub>CC</sub> = 5 V Load = 470 $\Omega$ to GND $V_{CC} = 5.25 \text{ V}$ $T_A = 70^{\circ}C$ Load = 470 $\Omega$ to GND See Note A V<sub>CC</sub> = 5 V T<sub>A</sub> = 25°C See Note A 3 V<sub>O</sub> - Y Output Voltage - V 3 $T_A = 0^{\circ}C$ V<sub>CC</sub> = 4.75 V V<sub>O</sub> – Y Output Voltage – V T<sub>A</sub> = 25°C 2 2 1 0 O 0 0 V<sub>I</sub> - Enable G Input Voltage - V VI - Enable G Input Voltage - V Figure 2 Figure 3 **OUTPUT VOLTAGE OUTPUT VOLTAGE ENABLE G INPUT VOLTAGE ENABLE G INPUT VOLTAGE** 6 6 $V_{CC}$ = 5 V Load = 470 $\Omega$ to $V_{CC}$ $V_{CC} = 5.25 \text{ V}$ Load = 470 $\Omega$ to V<sub>CC</sub> See Note B See Note B T<sub>A</sub> = 25°C 5 5 $V_{CC} = 5 V$ V<sub>CC</sub> = 4.75 V V<sub>O</sub>- Output Voltage - V V<sub>O</sub>- Output Voltage - V 4 4 $T_A = 70^{\circ}C$ 3 3 T<sub>A</sub> = 25°C $T_A = 0^{\circ}C$ 2 2 1 1 0 0 0 2 0 VI - Enable G Input Voltage - V V<sub>I</sub> - Enable G Input Voltage - V

NOTES: A. The A input is connected to VCC during the testing of the Y outputs and to ground during testing of the Z outputs.

Figure 4

B. The A input is connected to ground during the testing of the Y outputs and to VCC during the testing of the Z outputs.



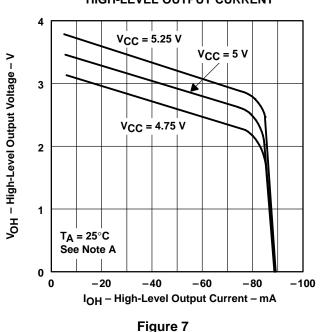
**HIGH-LEVEL OUTPUT VOLTAGE** 

### TYPICAL CHARACTERISTICS

### FREE-AIR TEMPERATURE 5 V<sub>CC</sub> = 5 V See Note A V<sub>OH</sub> - High-Level Output Voltage - V 4 $I_{OH} = -20 \text{ mA}$ 3 $I_{OH} = -40 \text{ mA}$ 2 1 0 0 10 20 30 40 50 60 70 80 T<sub>A</sub> - Free-Air Temperature - °C

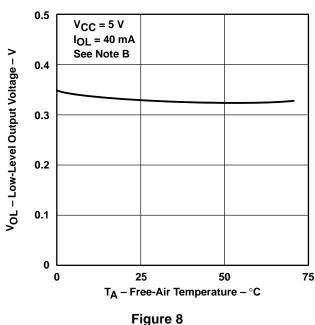
Figure 6

HIGH-LEVEL OUTPUT VOLTAGE **HIGH-LEVEL OUTPUT CURRENT** 



# LOW-LEVEL OUTPUT VOLTAGE

### vs FREE-AIR TEMPERATURE



**LOW-LEVEL OUTPUT VOLTAGE LOW-LEVEL OUTPUT CURRENT** 

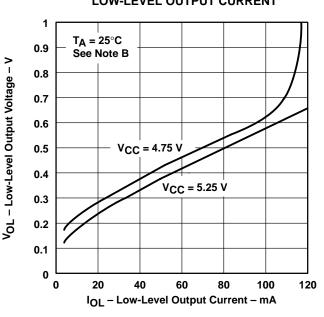


Figure 9

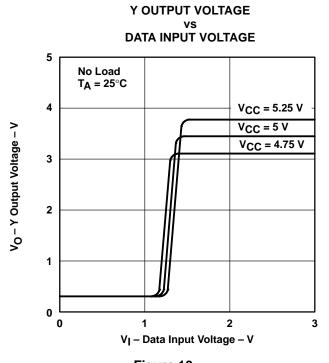
NOTES: A. The A input is connected to VCC during the testing of the Y outputs and to ground during testing of the Z outputs.

B. The A input is connected to ground during the testing of the Y outputs and to V<sub>CC</sub> during the testing of the Z inputs.



Y OUTPUT VOLTAGE

### **TYPICAL CHARACTERISTICS**



DATA INPUT VOLTAGE

No Load

TA = 70°C

TA = 0°C

Figure 10

Figure 11

V<sub>I</sub> – Data Input Voltage – V

0

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